

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/632,641	CHANG ET AL.
	Examiner Edward Wojciechowicz	Art Unit 2815

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
287	347, 348, 365, 401, 406, 411	4-1-05	EDJ